

PHOTON RT

UV-VIS-MWIR
Spectrophotometers for Coaters

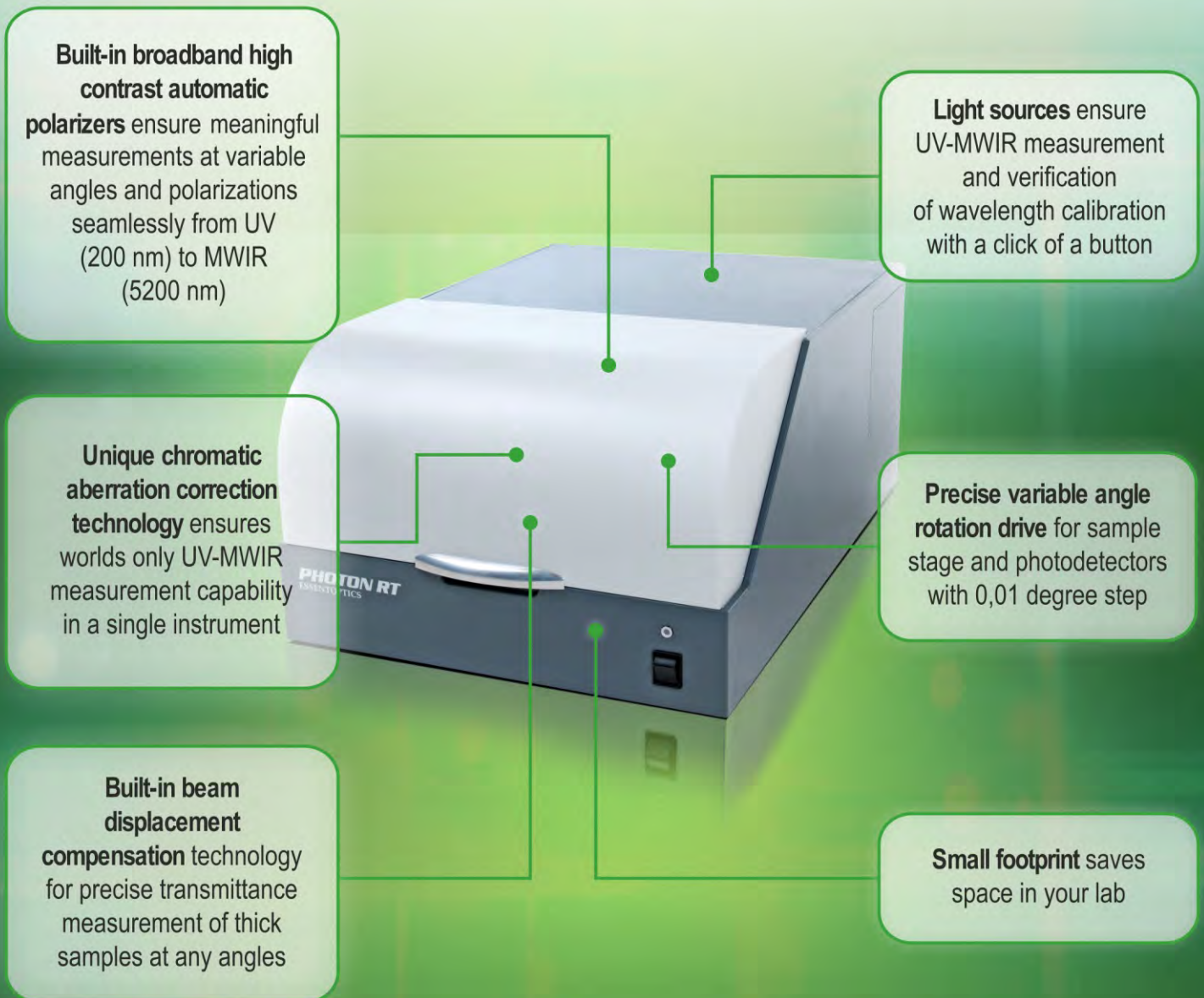


PHOTON RT

INTRODUCTION

PHOTON RT is the only spectrophotometer on the market designed exclusively for optical coaters. The instrument offers a set of fine-tuned, field-proven and unique features that add pleasure to metrology routine, improve measurement competences and help refine measurement procedures.

DESIGN ADVANTAGES

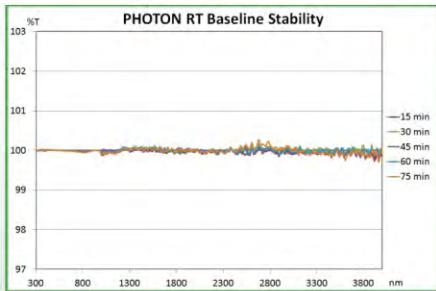


PHOTON RT: FAST FACTS

- 1) The only instrument designed exclusively for coaters
- 2) Unattended operation, no attachments required
- 3) Measure optics in minutes, not hours or days
- 4) No baseline recalibration with the change of angle of incidence or transmittance/absolute reflectance

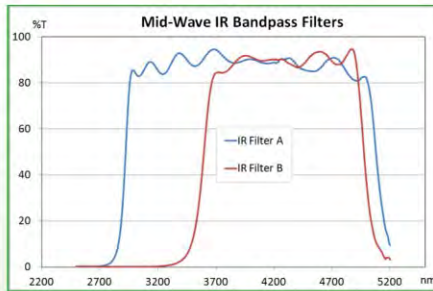
MEASUREMENT CAPABILITIES

Baseline Stability



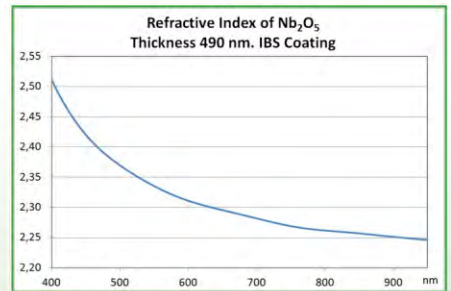
As shown above, PHOTON RT demonstrates very good baseline stability over time and at record-wide UV-MWIR wavelength range.

Mid-Wave Infrared Measurement



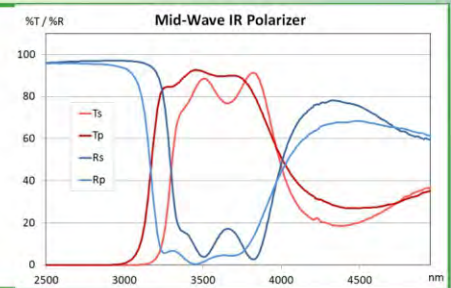
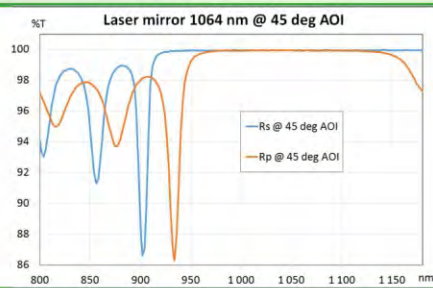
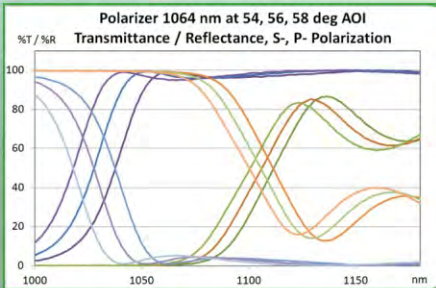
PHOTON RT is perfectly suited to meet the fast growing demand for precise measurements of parts with coatings designed for MWIR wavelength range (advanced laser systems and thermal vision instruments), both at normal AOI and at variable angles and polarizations.

Unattended Measurement and Calculation of Complex Refractive Index



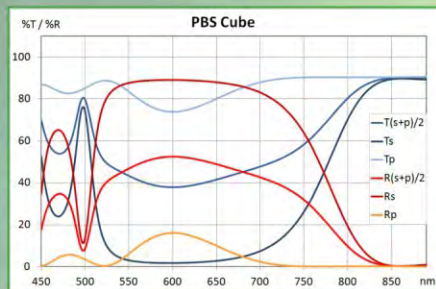
Single layer coatings can be measured with built-in proprietary software feature for subsequent instant calculation of complex refractive index and layer thickness. The example is shown for Nb2O5 layer, 490 nm thickness, produced by ion-beam sputtering technology.

Variable Angle and Polarization Dependent Measurements



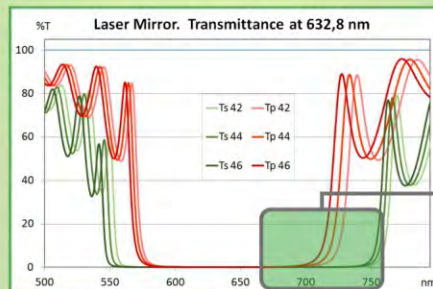
Powered with built-in high-contrast broadband polarizers, PHOTON RT spectrophotometer is uniquely differentiated with capability to measure at variable angles and polarizations unattended in just a few minutes.

Unattended Measurements of PBS cubes

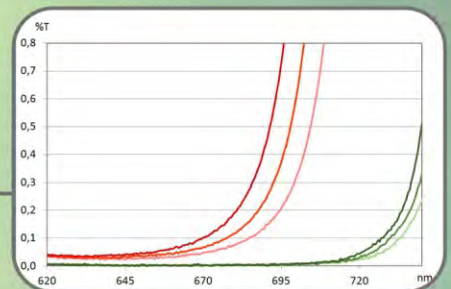


PBS cubes are among widely available yet challenging to measure optical components. Shown above, a PBS cube with uncoated front surfaces measured unattended in less than 2 minutes, ensuring the beam entering exactly the same point on the cube both for Ts/Tp and Rs/Rp measurements.

High Accuracy Measurements

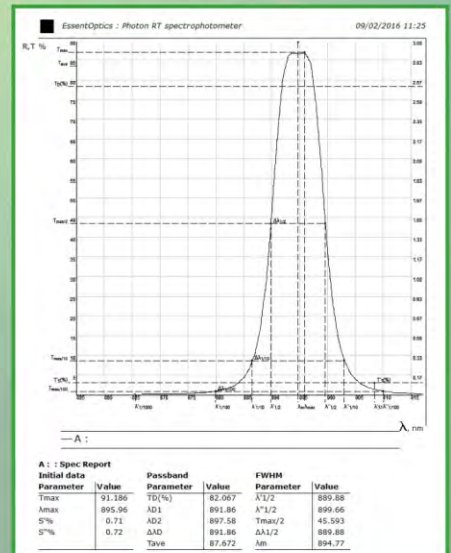


Transmittance measurement of laser mirror optimized for 632,8 nm at 44 degrees angle of incidence. The measurement results also shown for 42 and 46 degrees AOI to verify performance of the coating over +/- 2 degrees angle of deviation.



Qualitative and Quantitative Analysis of Measured Coatings

Yield Analyses and Spec Report – powerful software features helping optical experts to perform qualitative and quantitative analysis of typical coatings with a click of a button, like cut-off filters and narrow bandpass filters. The new time-saving and efficient software capabilities are used for QA/QC approval of the coatings against pre-set acceptance limits, and instant generation of specification data for analyzed spectra.



Specifications

PARAMETER	DESCRIPTION
OPTICAL CONFIGURATION	
Optical scheme of monochromator	Czerny-Turner
Optics	Mirror, Al + SiO ₂ , Al+MgF ₂
Reference channel	Yes
Wavelength sampling pitch, nm	0,5 to 100
Wavelength scanning speed, nm/min	3 000 (at 5 nm wavelength sampling pitch)
Spot size on the measured sample, mm	6x2
Photometric functions	%T, %R, A, D
Variable angle measurement	Transmittance: 0°-75° AOI Specular reflectance: 8°-75° AOI
Tuning pitch angle of sample table	0,01°
Turning pitch angle of photodetectors	0,01°
Positioning accuracy of the tuning pitch angle of sample table	0,01°
Effective wavelength range, nm (instrument configuration options)	185-1700, 185-3500, 190-4900, 380-1700, 380-3500, 380-5200
Spectral resolution, nm	
185 - 990 nm	0,6
990 - 2450 nm	1,2
2450 - 4900 / 5200 nm	2,4
Wavelength accuracy, nm	+/- 0,24
Wavelength repeat accuracy, nm	+/- 0,12
Scattered light level, % max (@ 532 nm)	< 0,002
Angle of beam divergence	+/- 1°
Photometric accuracy	Certified according to NIST SRM 930: +/- 0.003 Abs (1 Abs) Certified according to NIST SRM 1930: +/- 0.003 Abs (0.33 Abs), +/- 0.006 (2 Abs)
Photometric repeat accuracy	Certified according to NIST SRM 930: 0.0004 Abs (1 Abs) Certified according to NIST SRM 1930: 0.0001 Abs (0.33 Abs), 0.005 (2 Abs) Determined using 0.1-second accumulation, maximum deviation for 10 subsequent measurements
Stability of baseline (UV-VIS), %/hour **	0,1 (30 minutes warm-up time)
Light sources	Deuterium lamp, Halogen lamp, Hg-Ar wavelength calibration verification calibration lamp
Built-In broadband high-contrast polarizers, unattended operation	S, P, S+P+(S+P)/2, Average, user-defined S:P ratio for incident beam Wavelength ranges: 380-2200 nm, 220-2200 nm, 220-5200 nm, 380-5200 nm
SAMPLE COMPARTMENT	
Sample table	For measurement of transmission and reflection of plane samples with size bigger than 12x10 mm
Independent setting	Independent positioning for sample table and photodetectors unit
Synchronized setting	Synchronized positioning for sample table and photodetectors unit depending on the chosen photometric function (R or T)
Size of samples	Min. 12x10 mm – for measurement at 0-10 deg incidence angles. Min. 12x25 mm - for measurement at 10-75 deg incidence angles Max. sample size – up to Ø120mm
INTERFACE, DIMENSION AND WEIGHT	
Interface	USB 2.0
Power consumption, Wt	110
Power input	110/220 V, 50/60 Hz
Width x Depth x Height, mm (inches)	420 x 610 x 270 (16.5" x 24" x 10.5")
Net weight, kg (lbs)	45 kg (99 lbs)
Supply set	PHOTON RT Spectrophotometer, Operation Manual, USB cable, power cable, software package, spare halogen lamps.


株式会社 東京インスツルメンツ
TOKYO INSTRUMENTS, INC.
M u t u a l S a t i s f a c t i o n

<http://www.tokyoinst.co.jp/>

本 社 〒134-0088 東京都江戸川区西葛西6-18-14 Tビル TEL 03(3686)4711 FAX 03(3686)0831
 大阪営業所 〒532-0003 大阪市淀川区宮原4-1-46 新大阪北ビル TEL 06(6393)7411 FAX 06(6393)7055